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SILVACO

Parasitic Extraction Full Chip and Cell Level RC Extraction

Contents

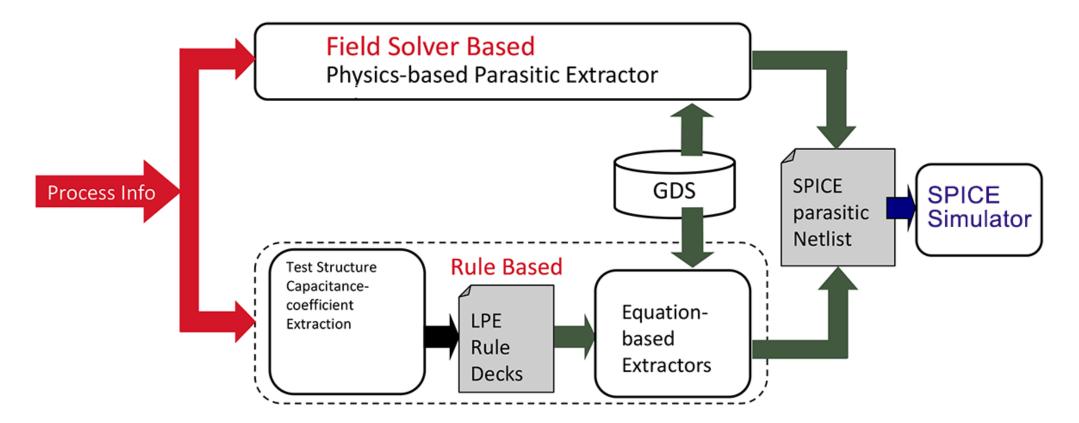
- Introduction
- Simulation Methodologies
- Rule Based
 - Parasitic database generation
- Field Solver
 - Field solver methods
 - Boundary element or finite element
- Summary

Introduction

- Many solution methodologies for RC extraction (RCX)
- Optimize solution methodology for each application
- A common platform maximizes user choice
- Consider intended user skill set, CAD versus TCAD
- Consider size and topology, versus simulation speed
- How much accuracy is really needed
- User choices are often technology dependent

Solution Methodologies

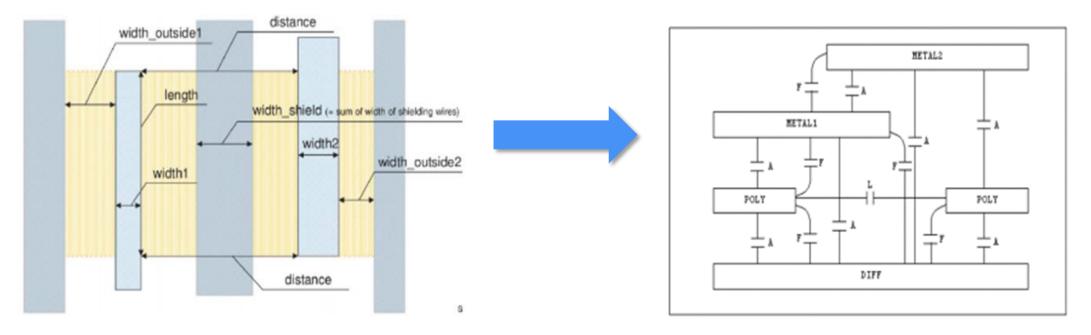
• Rule based (fastest) or Field solver based (most accurate)





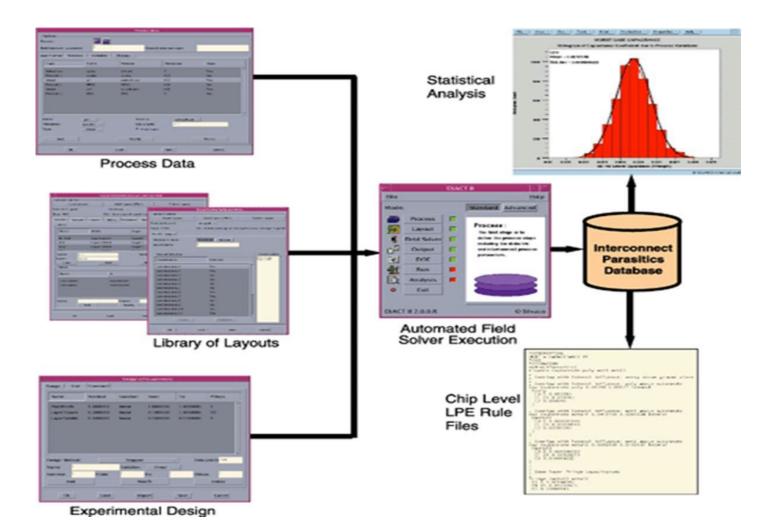
Rule Based

- Capacitance extract geometry from layout polygons
- Resistance count conductor length in "squares"
- Coefficient database converts polygons into C & R values





Parasitic Database Generation



- Generating the capacitance coefficient database for rule based extraction
- requires a field solver
- One time per technology
- Silvaco 'Exact' tool

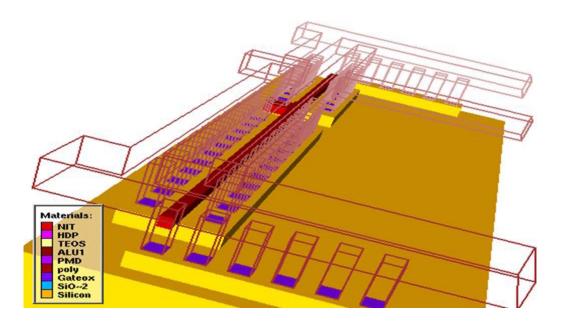
Field Solver Methods

- Field solver's have several methods to apply the physics to the physical representation of the structure
- Field solvers extract both capacitance and resistance
- Finite Difference and Finite Element Methods are:
 - Optimal for complex and curved 3d shapes
- Boundary Element and Random Walk Methods are:
 - Optimal for squared off "Manhattan" shapes
- Simulation speed versus shape complexity trade off
- Silvaco tools use field solvers from both categories

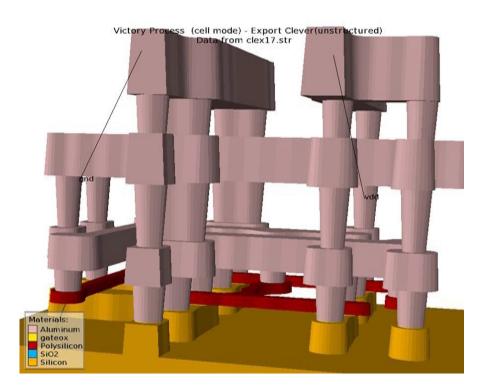


Boundary Element or Finite Element?

- For uniform layer thickness and Manhattan shapes
 - Boundary Element Method

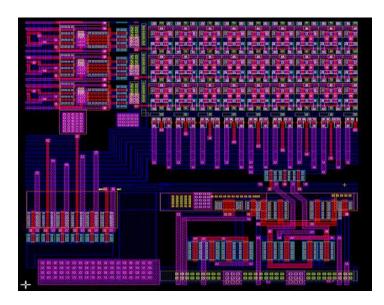


- For complex 3D shapes
 - Finite Element Method



Summary

- Rule based extraction used for most of the full chip
- Field solver based extraction for complex R & C layout
- Highest accuracy is required for critical cells
- Mix and match techniques within one design



Typical maximum cell size illustration for using field solver techniques



